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Application Number	10/825,811	
Filing Date	7/23/2003	
First Named Inventor	Christopher L. Chua	
Art Unit	2828	
Examiner Name	Tuan N. Nguyen	
Attorney Docket Number	A3316-US-NP	

	U.S. Patent Documents						
Examiner	Cite No.'	Document Number	Publication Date	Name of Patentes or	Pagas, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
Initials		Number-Kind Code ^{2 (J thous)}	MM-DD-YYYY	Applicam of Cited Document			
TN		US-6,208,681	03/27/2001	Thornton			
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Non Patent Literature Documents						
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TU		D.L. HUFFAKER, ET AL.: Appl, Phys. Lett, Vol 65, no 1 pp 97-99, 1994				
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TU		S. MUKAI, ETAL: Appl Phys. Lett, Vol 45, no8, pp834-835, 1984				
Examiner Signature		Juan Many Considered 8/23	100			

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicable.

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